

Search Notes

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HANH N. NGUYEN

Applicant(s)/Patent under
Reexamination

SHIKAYAMA ET AL.

Art Unit

2834

SEARCHED

Class	Subclass	Date	Examiner
310	12	6/6/2008	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR